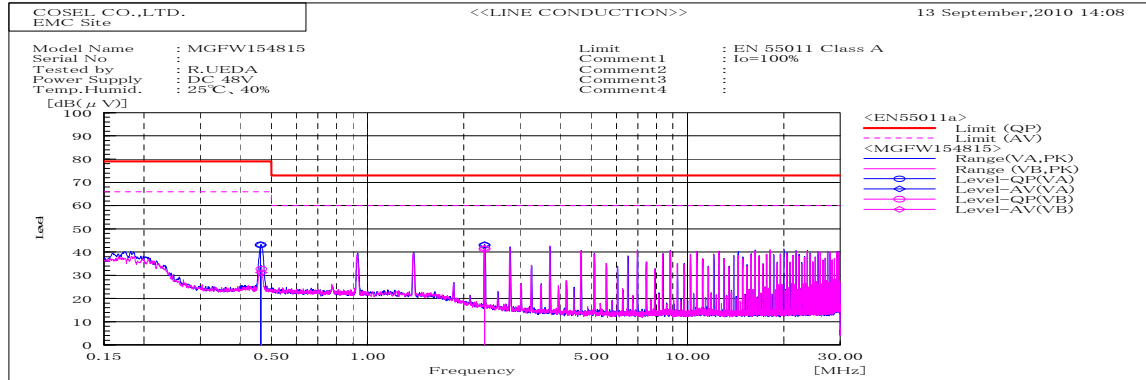
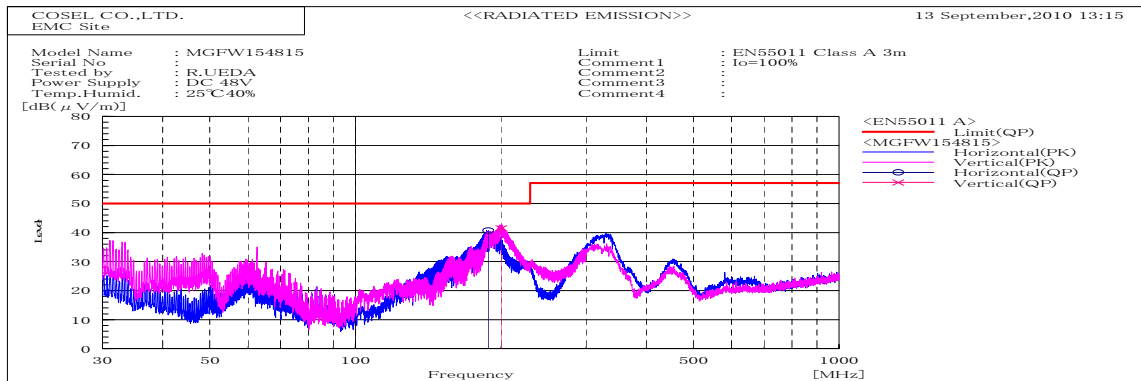


DATA SHEET		Date	21-Sep-10
Model	MGFW154815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46327		VA	33	32.9	10.1	43.1	43	79	66	35.9	23	Pass	
0.46578		VB	22.7	21.1	10	32.7	31.1	79	66	46.3	34.9	Pass	
2.3203		VA	32.7	33	10.2	42.9	43.2	73	60	30.1	16.8	Pass	
2.32034		VB	31.2	31.4	10.1	41.3	41.5	73	60	31.7	18.5	Pass	

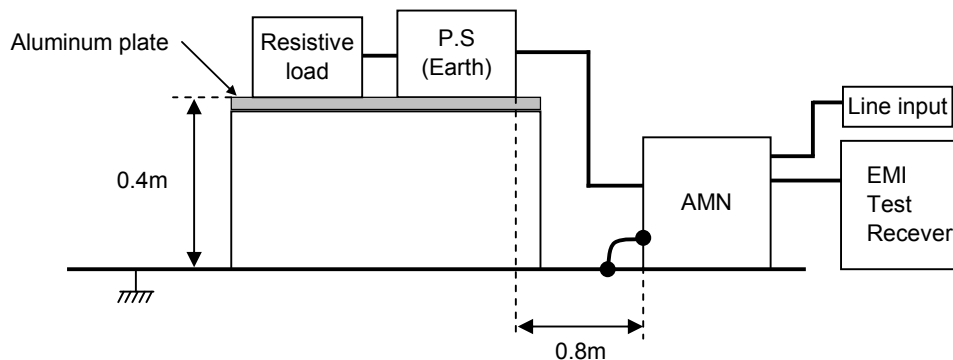


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
188.35	H	Stable	62.8		-22.1	40.7		50	9.3	Pass	103	14	
200.277	V	Stable	63.5		-22	41.5		50	8.5	Pass	133	224	

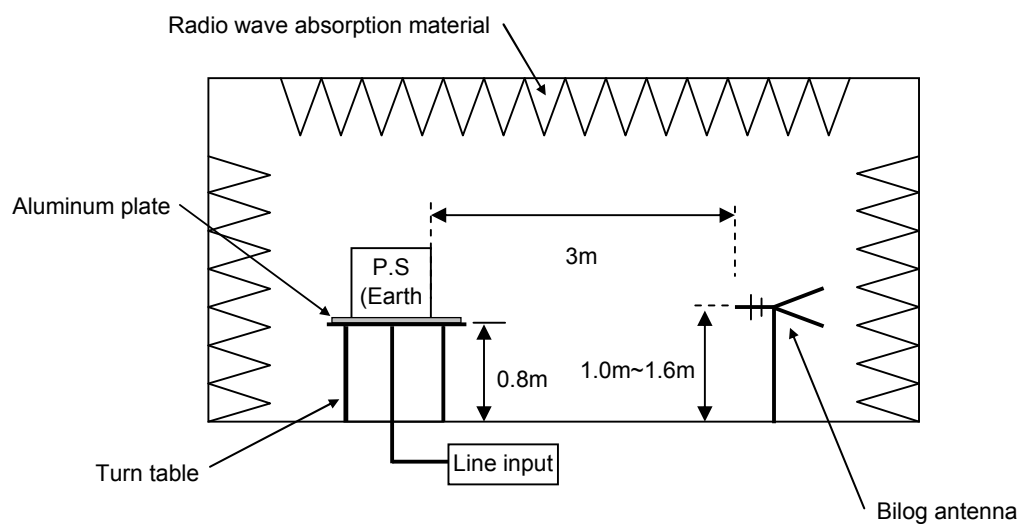
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

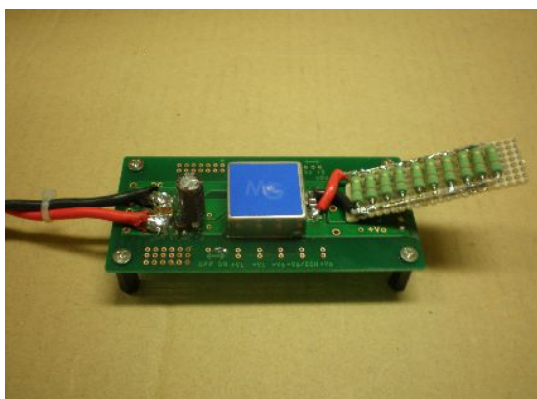


Conditions

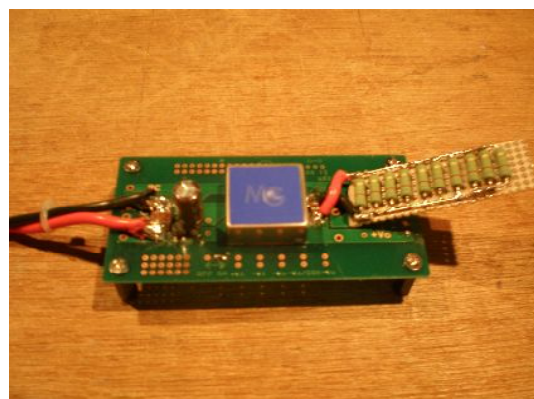
Test : EMI
 Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

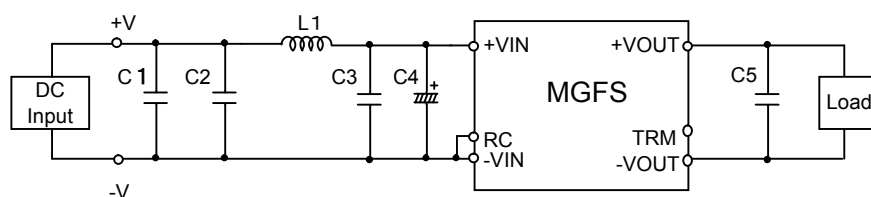


Fig.1 Testing circuitry 1

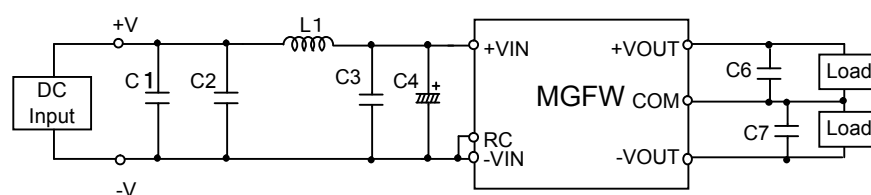


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)